

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 250847US2X		SERIAL NO. <u>10/810,713</u> New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Sotoshi YAMADA, et al.			
				FILING DATE Herewith		GROUP 2862	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AF	7-83884 ✓	03/31/95	Japan (with English Abstract)		x	
	AG	9-189682 ✓	07/22/97	Japan (with English Abstract)		x	
	AH	11-248685 ✓	09/17/99	Japan (with English Abstract)		x	
	AI	2002-90490 ✓	03/27/02	Japan (with English Abstract)		x	
	AJ						
	AK						
	AL						
	AM						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AN	Y. KATAOKA, et al. "Application of GMR Line Sensor to Eddy Current Testing Probe", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 27, No. 4, pp. 385-388, April 1, 2003					
	AO	Y. KATAOKA, et al. "Application of GMR Line Sensor to Eddy Current Testing", DIGESTS OF INTERMAG 2003, IEEE, CQ-07, April, 2003					
	AP	Sotoshi YAMADA, et al. "Inspection of Bare Printed Circuit Board Using Planar Type ECT Probe", REVIEW OF PROGRESS IN QUANTITATIVE NDE, P. 9, July 28, 2003					
	AQ	Yuzo FUKUDA, et al. "High Frequency and Small Field Amplitude Characteristics of GMR-SV Sensor for Eddy Current Testing", THE 27TH ANNUAL CONFERENCE OF MAGNETICS IN JAPAN, 19pC-1, p. 472, September 19, 2003					
	AR	K. CHOMUSUWAN, et al. "The GMR Sensor Utilization for PCB Inspection Based on Eddy-Current Testing Technique", THE 27TH ANNUAL CONFERENCE OF MAGNETICS IN JAPAN, 19pC-2, p. 473, September 19, 2003					
	AS	Y. FUKUDA, et al. "High-Frequency, Low-Amplitude Magnetic Field Characteristics of SV-GMR Sensor for ECT Technique", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 28, No. 3, pp. 405-408, March 1, 2004					
	AT	K. CHOMSUWAN, et al. "GMR Sensor Utilization for PCB Inspection Based on the Eddy-Current Testing Technique", TRANSACTIONS OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 4, No. 1, pp. 39-42, February 1, 2004					
	AU	T. MIYAGOSHI, et al. "Feasibility of Inspecting Defects in Printed Circuit Boards by Using Eddy-Current Testing Techniques", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 23, No. 4-2, pp. 1613-1616, 1999					
	UV	S. YAMADA, et al. "Trend of Detection Techniques Using Planar-Type Micro-Eddy-Current Testing Probes", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 23, No. 7, pp. 1817-1825, 1999					
	AW						<input type="checkbox"/> Additional References sheet(s) attached
Examiner <u>jaeymsahoe</u>					Date Considered <u>11/8/05</u>		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							